

Notice of References Cited	Application/Control No. 10/823,784	Applicant(s)/Patent Under Reexamination UHLMANN ET AL.	
	Examiner Amanda M. Shaw	Art Unit 1634	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,078,168	07-2006	Sylvan, Anna	435/6
*	B	US-2002/0086324	07-2002	Laird et al.	435/6
	C	US-			
	D	US-			
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	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Uhlmann, Karen et al. Changes in methylation patterns identified by two dimensional DNA fingerprinting. 1999. Electrophoresis. Vol 20 pages 1748-1755.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.